

**Search Notes**

Application/Control No.

10/765,370

Examiner

Hiep Nguyen

Applicant(s)/Patent under  
Reexamination

MCRAE ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attached	12.13.05	<i>[Signature]</i>